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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/698,739	10/30/2003	Binh Vo	015114-068400US	3284
26059 7590 07/16/2009 TOWNSEND AND TOWNSEND AND CREW LLP/ 015114 TWO EMBARCADERO CENTER 8TH FLOOR SAN FRANCISCO, CA 94111-3834				
EXAMINER NGUYEN, STEVE N				
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary

Application No.

10/698,739

Applicant(s)

VO ET AL.

Examiner

STEVE NGUYEN

Art Unit

2117

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 04 June 2009.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-22 and 25 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-22 and 25 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 30 October 2003 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
- Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) ☐ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☐ Information Disclosure Statement(s) (PTO/S508)
Paper No(s)/Mail Date _____

- 4) ☐ Interview Summary (PTO-413)
Paper No(s)/Mail Date _____
- 5) ☐ Notice of Informal Patent Application
- 6) ☐ Other: _____

DETAILED ACTION

Claims 1-22 and 25 are currently pending.

Response to Arguments

Applicant's arguments with respect to pending claims have been considered but are moot in view of the new ground(s) of rejection.

Claim Objections

Claim 25 objected to because of the following informalities: Claim 25 should end with a period. Appropriate correction is required.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

The factual inquiries set forth in *Graham v. John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

1. Determining the scope and contents of the prior art.

2. Ascertaining the differences between the prior art and the claims at issue.
3. Resolving the level of ordinary skill in the pertinent art.
4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

Claims 1-3, 5-10, and 12-14, 21-22, and 25 rejected under 35 U.S.C. 103(a) as being unpatentable over Culbertson et al (US Pat. 5,790,771; hereinafter referred to as Culbertson) in view of Mortensen (US Pat. 6,772,402).

As per claims 1 and 9:

Culbertson teaches a method for isolating failed routing resources on a programmable integrated circuit, the method comprising:

- receiving a first plurality of failed test patterns, wherein a test pattern includes program bits that define how routing resources on the programmable integrated circuit are connected to form a test path (col. 6, lines 34-42), wherein a test pattern is designated as failing when a result from a test path is erroneous, wherein the result of the failed test path is created by applying one or more test values to the failed test path (col. 6, lines 43-52);
- identifying a subset of the routing resources on the programmable integrated circuit based on the first plurality of failed test patterns (resources 71b-71d in Fig. 5C are identified based on the failed test patterns 93-95), wherein the subset comprises one or more routing resources that respectively occur in the most failed test paths (resources 71b-71d occurred in failed test paths 93-95 in Fig. 5C and also in failed test path 81 in Fig. 5B); and
- generating new test patterns including program bits that define new test paths for testing the subset of the routing resources (Fig. 4B; 59).

Not explicitly disclosed by Culbertson is receiving a second plurality of failed test patterns resulting from applying one or more test values to tests paths on one or more other programmable integrated circuits, wherein the other programmable circuits have a same architecture as the programmable integrated circuit. However, Mortensen in an analogous art teaches receiving and merging failed test patterns resulting from applying test values to tests paths on other programmable integrated circuits having the same architecture (col. 8, lines 49-59).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to test a design having multiple ALU circuits using the teachings of Culbertson. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that applying the testing of Culbertson to a programmable circuit design such as that of Mortensen was recognized as part of the ordinary capabilities of one skilled in the art.

As per claim 2:

Culbertson further teaches the method according to claim 1 further comprising: testing the new test patterns using a test system to isolate routing resources among the subset of the routing resources that caused the erroneous results in the failed test patterns (Fig. 2).

As per claims 3 and 13:

Culbertson further teaches the wherein generating the new test patterns includes program bits that define new test paths for testing every routing resource of the subset;

wherein for each routing resource of the subset, the new test paths route through every combination of fan-in resources and fan-out resources that are programmably connectable to that routing resource of the subset (col. 6, lines 26-30, 67).

As per claim 5:

Culbertson further teaches the method according to claim 1 wherein each of the failed test paths and the new test paths connect a control point to an observation point on the programmable integrated circuit (col. 4, line 59).

As per claims 6 and 14:

Culbertson teaches the method above, but does not explicitly disclose wherein the routing resources have more than 1000 times as many routing resources as the subset of routing resources. However, one of ordinary skill in the art at the time the invention was made would have recognized that a modern circuit would have contained many thousands of routing resources.

As per claims 7 and 10:

Culbertson further teaches receiving a test log file that indicates the observation points for the failed test paths (Fig. 2; 32).

As per claim 8:

Culbertson teaches the method above. Not explicitly disclosed is wherein identifying the subset of the routing resources that occur most frequently in the failed test paths further comprises: extracting the routing resources that are connected along each of the failed test paths using a connectivity graph. However, it would have been

obvious to one of ordinary skill in the art to do so because Culbertson shows the extraction of failed paths using the drawing of Fig. 5.

As per claim 12:

Culbertson further teaches the computer program product of claim 9 further comprising: code for testing the new test patterns to isolate routing resources among the subset that caused the erroneous results in the failed test patterns (Fig. 4).

As per claim 21:

Culbertson further teaches the method of claim 1, wherein each of the new test paths is used to determine whether the resources of the subset have actually failed (col. 5, lines 38-39).

As per claim 22:

Culbertson further teaches the method of claim 1, wherein the erroneous result of a failed test path is an output value of the failed test path that does not equal an expected value (col. 6, lines 51-57).

As per claim 25:

Culbertson and Mortensen teach the method of claim 1, wherein generating new test patterns includes program bits that define new test paths for testing a first routing resource of the subset of the routing resources (Fig. 4B; 59), wherein each of the new test paths includes: the first routing resource (Fig. 5C; any one of 71b, 71c, or 71d); and a combination, not included in the other new test paths, of resources that are programmably connectable to the first routing resource (Fig. 14; col. 9, lines 11-14).

Not explicitly disclosed by Culbertson is the combination of routing resources programmably connectable to the first routing resource are fan-in and fan- out resources. However, Culbertson states that the routing resources shown in Fig. 1 could be fan-in and fan- out resources (col. 4, line 59). Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to include combinations of fan-in and fan- out resources in the new test paths. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have been motivated to do so since it is suggested by Culbertson.

Also not explicitly disclosed by Culbertson is wherein the new test paths test every combination of fan-in and fan-out resources that are programmably connectable to the first routing resource. However, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to test every combination of fan-in and fan-out resources that are programmably connectable to the first routing resource. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because the key to isolating a faulty resource is redundant testing in which each resource is tested multiple times, each time grouped with a different set of other resources (col. 6, lines 26-29).

Claims 15-20 rejected under 35 U.S.C. 103(a) as being unpatentable over Culbertson
As per claim 15:

Culbertson teaches a computer system for isolating failed routing resources on a programmable integrated circuit, the computer system comprising a computer readable medium for directing a processor to isolate failed routing resources on a programmable integrated circuit, the computer readable medium comprising:

- code for a statistical failure isolation (SFI) tool, wherein the SFI tool:
- (a) receives a file (col. 5, lines 41-43) including a plurality of failed test patterns that generated erroneous results when test values were applied to a set of failed test paths (col. 6, lines 34-42), wherein a test pattern includes program bits that define how routing resources on the programmable integrated circuit are connected to form a test path (col. 6, lines 43-52);
- (b) determines routing resources along each failed test path (Fig. 5B);
- (d) identifies a subset of the routing resources based only on the test patterns that have failed (resources 71b-71d in Fig. 5C are identified based on the failed test patterns 93-95), wherein the subset comprises one or more resources having the highest number of occurrences (resources 71b-71d occurred in failed test paths 93-95 in Fig. 5C and also in failed test path 81 in Fig. 5B); and
- code for an adaptive failure isolation (AFI) tool that subsequent to completion of (b)-(d) generates new test patterns including program bits that define new test paths for testing the subset of the routing resources (Fig. 4B; 59).

Not explicitly disclosed by Culbertson is the SFI tool calculates a total number of occurrences of each resource in the failed test paths received in the file, at least one resource occurring in two failed test paths. However, Culbertson teaches identifying

each resource in the failed test paths in a lookup table (col. 5, lines 48-54). Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to calculate the total number of occurrences of each resource in the failed test paths. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that each of the resources would have been identified multiple times in the redundant testing (col. 6, lines 27-30); and that keeping a count was only a matter of design choice accounted for by Culbertson in col. 5, lines 65-67.

As per claim 16:

Culbertson further teaches receiving a test log file that indicates the observation points for the failed test paths (Fig. 2; 32).

As per claim 17:

Culbertson further teaches the computer program product of claim 9 further comprising: code for testing the new test patterns to isolate routing resources among the subset that caused the erroneous results in the failed test patterns (Fig. 4).

As per claim 18:

Culbertson further teaches the wherein generating the new test patterns includes program bits that define new test paths for testing every routing resource of the subset; wherein for each routing resource of the subset, the new test paths route through every combination of fan-in resources and fan-out resources that are programmably connectable to that routing resource of the subset (col. 6, lines 26-30, 67).

As per claim 19:

Culbertson teaches the method above, but does not explicitly disclose wherein the routing resources have more than 1000 times as many routing resources as the subset of routing resources. However, one of ordinary skill in the art at the time the invention was made would have recognized that a modern circuit would have contained many thousands of routing resources.

As per claim 20:

Culbertson teaches the method above. Not explicitly disclosed is wherein identifying the subset of the routing resources that occur most frequently in the failed test paths further comprises: extracting the routing resources that are connected along each of the failed test paths using a connectivity graph. However, it would have been obvious to one of ordinary skill in the art to do so because Culbertson shows the extraction of failed paths using the drawing of Fig. 5.

Claims 4 and 11 rejected under 35 U.S.C. 103(a) as being unpatentable over Culbertson in view of Abramovici et al (US Pat. 6,966,020; hereinafter referred to as Abramovici).

As per claims 4 and 11:

Culbertson teaches the method above. Not explicitly disclosed is wherein generating the new test patterns for the subset of the routing resources further comprises: generating new test patterns for test paths that route through clock and clear

signal routing resources. However, Abramovici teaches programmable logic of a boundary-scan interface (col. 5, lines 59-62).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to generate new test patterns for test paths that route through the clock and clear signal routing resources necessarily present in a boundary scan interface. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that the routing resources of Culbertson could have been used in a boundary scan interface (Culbertson; col. 4, lines 56-60).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to STEVE NGUYEN whose telephone number is (571)272-7214. The examiner can normally be reached on M-F, 10am-6:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kevin Ellis can be reached on (571) 272-4205. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Steve Nguyen
Examiner
Art Unit 2117

/Kevin L Ellis/
Supervisory Patent Examiner, Art Unit 2117